

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



22469

PATENT TRADEMARK OFFICE

Art Unit :
Examiner :
Serial No. : 10/019,819
Filed : December 21, 2001
PCT No. : PCT/EP00/04739
PCT Filed : May 24, 2000
Inventors : Christoph Räth
: Gregor Morfill
Title : METHOD AND
: DEVICE FOR
: SEGMENTING A
: POINT DISTRIBUTION

Docket: 1380-01
Confirmation No.: 9974

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Dated: March 28, 2002

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Washington, DC 20231

Sir:

We submit herewith the usual Form PTO-1449 together with copies of publications listed therein. They are submitted to comply with the Applicants' duty of disclosure under 37 C.F.R. §1.56 and are believed related to this application.

We are submitting this in the spirit of voluntary disclosure and look forward with interest to the Examiner's action at an early date on the merits of the case.

It is accordingly requested that the Information Disclosure Statement be officially entered in the file of this case and that appropriate notification be made that it was considered in the prosecution of the case.

Respectfully submitted,

T. Daniel Christenbury
Reg. No. 31,750
Attorney for Applicants

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Form PTO-1449

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	DE 43 17 746 A1 (Corr US Patent No. 5,822,466)	12/1/84	Germany			X	
	AM	DE 196 33 693 C1 (Corr. US Patent No. 5,923,780)	11/20/97	Germany			X	
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OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	M. Tuceryan et al., Handbook of Pattern Recognition and Computer Vision, "Texture Analysis", World Scientific, Publishing, 1993, pp 235-276
		R. C. Dubes, Handbook of Pattern Recognition and Computer Vision, "Cluster Analysis and Related Issues", World Scientific Publishing, 1993, pp 3-32
	AS	R. M. Haralick, Proceedings of the IEEE, "Statistical and Structural Approaches to Texture", Vol. 67, No. 5, May 1979, pp 786-804
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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	AR	F. W. Campbell et al., J. Physiol, "Application of Fourier Analysis to the Visibility of Gratings", Vol 197, 1968, pp 551-566
	AS	R. De Valois et al., Vision Res., "Spatial Frequency Selectivity of Cells in Macaque Visual Cortex", Vol 22, 1982, pp 545-559
	AT	A.K. Jain et al., Pattern Recognition, "Unsupervised Texture Segmentation Using Gabor Filters", Vol 24, No. 12, 1991, pp 1167-1186

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	AS	A.M. Bensaid et al., Pattern Recognition, "Partially Supervised Clustering for Image Segmentation" Vol. 29, 1996, pp 859-871
	AT	L. Abele, "Bildsegmentation mittels struktureller Texturanalyse", Springer-Verlag, 1979, pages 269-279 (with abstract)

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	AS	T. Randen, J.H. Husoy, IEEE Transactions on Pattern Analysis and Machine Intelligence, "Filtering for Texture Classification: A Comparative
		Study", Vol. 21, No. 4, pp. 291-310
	AT	Bela Julesz, Review of Modern Physics, "Early Vision and Focal Attention", Vol. 63, 1991, pp 735-772

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	AR	Y. Hu et al., IEE Proc.-Vis. Image Signal Process., "Textured Image Segmentation by Context Enhanced Clustering", Vol. 141 No. 6, 12/94, pp 413-421
	AS	D.H. Ballard et al., Computer Vision, "Texture as a Pattern Recognition Problem", pp 181-184
	AT	I. Pitas et al., IEE, "Texture Analysis and Segmentation of Seismic Images", Conf. 14, 1989, pp 1437-1440

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